πf_{7/2} strength distribution in neutron-rich copper: the ⁷²Zn(d,³He)⁷¹Cu transfer reaction

S Franchoo, P Morfouace, M Assié, F Azaiez, D Beaumel, N De Séréville, S Giron, F Hammache, L Lefebvre, I Matea, A Matta, M Niikura, J-A Scarpaci, I Stefan, IPNO, France S Boissinot, A Corsi, A Gillibert, V Lapoux, C Louchart, L Nalpas, E Pollacco, Irfu, France J Burgunder, L Caceres, A Lepailleur, O Sorlin, C Stodel, J-C Thomas, Ganil, France I Martel, G Marquinez, A Sanchez, University of Huelva, Spain S Grévy, CENBG, France Z Dombradi, D Sohler, Z Vajta, Atomki, Hungary D Napoli, J Valiente Dobon, LNL, Italy D Mengoni, F Recchia, University of Padova, Italy R Borcea, M Stanoiu, IFIN HH, Romania B Fernandez-Dominguez, University of Santiago, Spain J Elseviers, University of Leuven, Belgium Level structure of neutron-rich copper isotopes $_{29}$ Cu = $_{28}$ Ni x π



S Franchoo et al, PRL 81 (1998)



Y Kudryavtsev et al, NIM B267 (2009)

⁷⁵Cu ground-state spin



 $A = \mu B/IJ$

K Flanagan et al, PRL 103 (2009)



	in source	collinear
resolution	>1 GHz	<100 MHz
count rate	10 /s	150 /s

Effect of tensor force on proton SPE in nickel



T Otsuka et al, PRL 104 (2010)



also: A Lisetskiy et al, PRC 70 (2005), M Honma et al, PRC 80 (2009)...

Well described by theory but needs spectroscopic factors

Measure evolution of $\pi f_{7/2}$ strength in transfer

⁷⁰Zn(d,³He)⁶⁹Cu at 12 MeV/u



Zeidman & Nolen, PRC 18 (1978) 2122

Transfer & coulex



extracted from Zeidman & Nolen, PRC 18 (1978)

Experiment



low cross section, high beam intensity: sampling ionisation chamber

low energy: thin 20 μ m Si for Δ E

<u>setup:</u> 2xCATS: beam tracking SSSD+MUST2: light ejectile IC+plastic: heavy ejectile

- **AEE** identification

4x MUST2 forwards

20 µm SSSD

CD target

2x MUST2 backwards

CATS

38 AMeV

⁷²Zn

2x MUST2 sideways

Ionisation chamber



Ionisation chamber



Particle identification



 Δ E-E in second and third stage of Must2: 300µ vs CsI (higher energies)

Particle identification



 Δ E-E in first and second stage of Must2: 20µ vs 20+300µ (lower energies)



TOF-E without correction

20µ SSSD



thickness defect: local density correction

Particle identification



TOF-E corrected for thickness defect of 20μ SSSD

